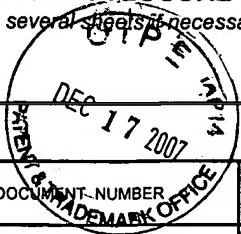


INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				ATTY DOCKET NO. TROLOGY 02.02		APPLICATION NO. 10/536.576	
				APPLICANT(S) Szwaykowski et al.			
				FILING DATE February 6, 2006		GROUP ART UNIT	



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INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. TROLOGY 02.02	APPLICATION NO. 10/536,576
	Szywaykowski et al.	
	FILING February 6, 2006	GROUP ART

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
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